

64K x 24 Static RAM Module

Features

- High-density 1.5M SRAM module
- **High-speed CMOS SRAMs**
- Access time of 25 ns
- 56-pin, 0.5-inch-high ZIP package
- Low active power
 - -2.8W (max. for $t_{AA} = 25$ ns)
- SMD technology
- TTL-compatible inputs and outputs
- Commercial temperature range
- **Small PCB footprint**
 - 1.05 sq. in.

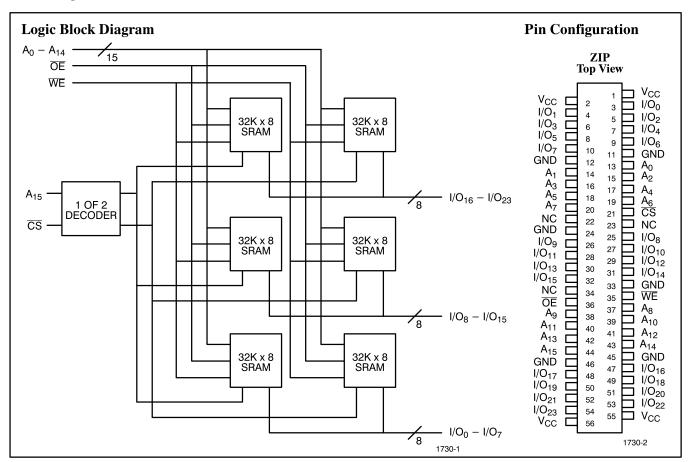
Functional Description

The CYM1730 is a high-performance 1.5M static RAM module organized as 64K words by 24 bits. This module is constructed using six 32K x 8 static RAMs in SOJ packages mounted onto an epoxy laminate board with pins.

Writing to the device is accomplished when the chip select (\overline{CS}) and write enable (\overline{WE}) inputs are both LOW. Data on the input/ output pins (I/O₀ through I/O₂₃) of the device is written into the memory location specified on the address pins (A₀ through A_{15}).

Reading the device is accomplished by taking the chip select (\overline{CS}) and output enable (\overline{OE}) LOW while write enable (\overline{WE}) remains HIGH. Under these conditions, the contents of the memory location specified on the address pins will appear on the input/output pins.

The input/output pins remain in a high-impedance state unless the module is selected, outputs are enabled, and write enable is HIGH.



Selection Guide

	1730-25	1730-30	1730-35
Maximum Access Time (ns)	25	30	35
Maximum Operating Current (mA)	510	510	510
Maximum Standby Current (mA)	180	180	180



Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

DC Voltage Applied to Outputs

Operating Range

Range	Ambient Temperature	v_{cc}
Commercial	0° C to $+70^{\circ}$ C	$5V \pm 10\%$

Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	Min.	Max.	Unit
V_{OH}	Output HIGH Voltage	$V_{\rm CC}$ = Min., $I_{\rm OH}$ = -4.0 mA	2.4		V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 8.0 mA		0.4	V
V_{IH}	Input HIGH Voltage		2.2	$V_{CC} + 0.3$	V
V_{IL}	Input LOW Voltage		-0.3	0.8	V
I_{IX}	Input Load Current	$GND \le V_I \le V_{CC}$	-20	+20	μΑ
I_{OZ}	Output Leakage Current	$\begin{aligned} & \text{GND} \leq V_{\text{O}} \leq V_{\text{CC}}, \\ & \text{Output Disabled} \end{aligned}$	-10	+10	μΑ
I_{CC}	V _{CC} Operating Supply Current	$V_{CC} = Max., I_{OUT} = 0 \text{ mA}, \overline{CS} \leq V_{IL}$		510	mA
I_{SB1}	Automatic CS Power-Down Current ^[1]	Max. V_{CC} , $\overline{CS} \ge V_{IH}$, Min. Duty Cycle = 100%		180	mA
I_{SB2}	Automatic CS Power-Down Current ^[1]	Max. V_{CC} , $\overline{CS} \ge V_{CC} - 0.2V$, $V_{IN} \ge V_{CC} - 0.2V$ or $V_{IN} \le 0.2V$		180	mA

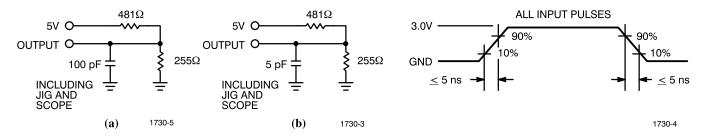
Capacitance^[2]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = 5.0$ V	50	pF
C _{OUT}	Output Capacitance	· (C = 3.0 ·	20	pF

Notes:

2. Tested on a sample basis.

AC Test Loads and Waveforms



Equivalent to: THÉVENIN EQUIVALENT OUTPUT O 167Ω 1.73V

^{1.} A pull-up resistor to V_{CC} on the \overline{CS} input is required to keep the device deselected during V_{CC} power-up, otherwise I_{SB} will exceed values given.



Switching Characteristics Over the Operating Range^[3]

		1730-25		1730-30		1730-35		
Parameter	Parameter Description		Max.	Min.	Max.	Min.	Max.	Unit
READ CYCLE	READ CYCLE							
t _{RC}	Read Cycle Time	25		30		35		ns
t_{AA}	Address to Data Valid		25		30		35	ns
t _{OHA}	Output Hold from Address Change	5		5		5		ns
t _{ACS}	CS LOW to Data Valid		25		30		35	ns
t _{DOE}	OE LOW to Data Valid		12		15		20	ns
t _{LZOE}	OE LOW to Low Z	3		3		3		ns
t _{HZOE}	OE HIGH to High Z		10		15		20	ns
t _{LZCS}	CS LOW to Low Z ^[4]	5		5		5		ns
t _{HZCS}	CS HIGH to High Z ^[4, 5]		10		15		15	ns
WRITE CYCLI	E[6]	•						
$t_{ m WC}$	Write Cycle Time	25		30		35		ns
t _{SCS}	CS LOW to Write End	20		25		30		ns
$t_{ m AW}$	Address Set-Up to Write End	22		25		30		ns
t _{HA}	Address Hold from Write End	2		2		2		ns
t _{SA}	Address Set-Up to Write Start	2		2		2		ns
t _{PWE}	WE Pulse Width	20		23		25		ns
$t_{ m SD}$	Data Set-Up to Write End	13		15		20		ns
t _{HD}	Data Hold from Write End	2		2		2		ns
t _{LZWE}	WE HIGH to Low Z	3		3		5		ns
t _{HZWE}	WE LOW to High Z ^[5]	0	10	0	10	0	15	ns

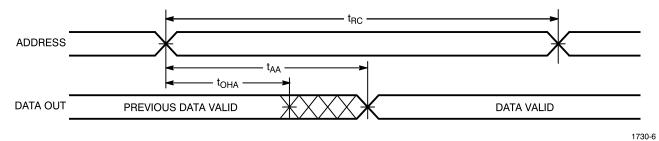
Notes:

- Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
- 4. At any given temperature and voltage condition, t_{HZCS} is less than t_{LZCS} for any given device.
- thzoe, thzcs, and tzzeare specified with C_L = 5 pF as in part (b) of AC Test Loads and Waveforms. Transition is measured ±500 mV from steady-state voltage.
- 6. The internal write time of the memory is defined by the overlap of \overline{CS} LOW and \overline{WE} LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input setup and hold timing should be referenced to the rising edge of the signal that terminates the write.



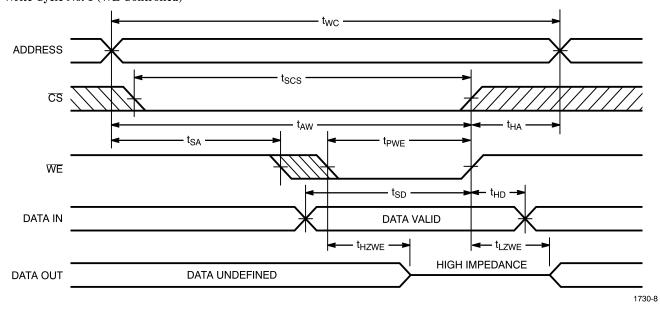
Switching Waveforms

Read Cycle No. 1^[7, 8]



Read Cycle No. $2^{[7, 9]}$ CS t_{ACS} ΟE t_{HZOE} · t_{DOE} - t_{HZCS} t_{LZOE} HIGH IMPEDANCE HIGH IMPEDANCE DATA VALID DATA OUT t_{LZCS} t_{PD} ICC V_{CC} SUPPLY CURRENT 50% ISB 1730-7

Write Cycle No. 1 ($\overline{\text{WE}}$ Controlled)[6, 10]

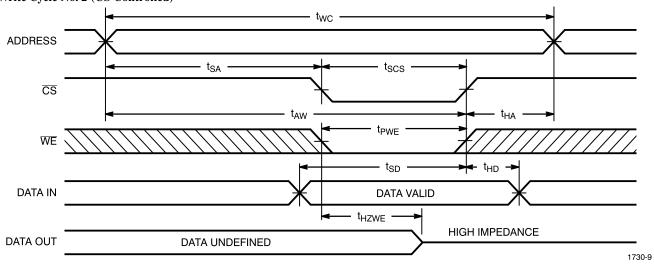


- Notes: 7. WE is HIGH for read cycle.
- 8. Device is continuously selected, $\overline{CS} = V_{IL}$ and $\overline{OE} = V_{IL}$.
- 9. Address valid prior to or coincident with $\overline{\text{CS}}$ transition LOW.
- 10. Data I/O will be high impedance if $\overline{OE} = V_{IH}$.



Switching Waveforms (continued)

Write Cycle No. 2 ($\overline{\textbf{CS}}$ Controlled)[6, 10, 11]



Note:
11. If $\overline{\text{CS}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ HIGH, the output remains in a high-impedance state.

Truth Table

CS	WE	ŌĒ	Input/Outputs	Mode
Н	X	X	High Z	Deselect/Power-Down
L	Н	L	Data Out	Read Word
L	L	X	Data In	Write Word
L	Н	Н	High Z	Deselect

Ordering Information

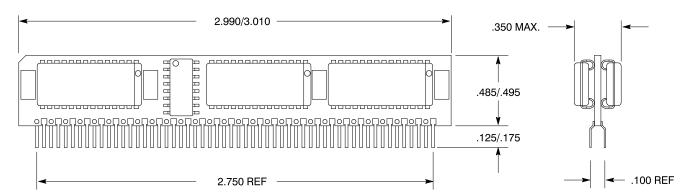
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CYM1730PZ-25C	PZ07	56-Pin ZIP Module	Commercial
30	CYM1730PZ-30C	PZ07	56-Pin ZIP Module	Commercial
35	CYM1730PZ-35C	PZ07	56-Pin ZIP Module	Commercial

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Package Diagram

56-Pin ZIP Module PZ07



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